TOSHIBA CMOS Linear Integrated Circuit Silicon Monolithic

TC75S56F,TC75S56FU,TC75S56FE

Single Comparator

The TC75S56F/TC75S56FU/TC75S56FE is a CMOS general-purpose single comparator. The device can operate off a single power supply and draws a lower supply current than a conventional bipolar general-purpose comparator. This device's push-pull output stage can be directly connected to TTL or CMOS logic ICs, among others.

Features

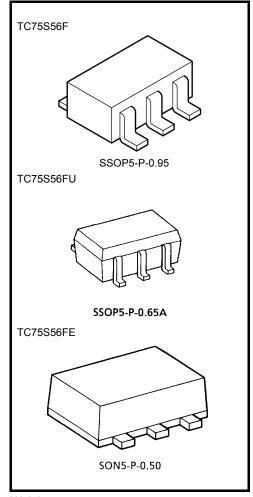
• Low-current power supply : $IDD = 10 \mu A \text{ (typ.)}$

• Single power supply operation

Wide common mode input voltage range: VSS~VDD - 0.9 V

• Push-pull output circuit

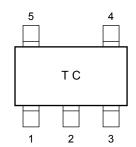
- Low input bias current
- · Small package



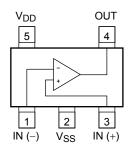
Weight

SSOP5-P-0.95 : 0.014 g (typ.) SSOP5-P-0.65A : 0.006 g (typ.) SON5-P-0.50 : 0.003 g (typ.)

Marking (top view)



Pin Connection (top view)



Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Supply voltage		V _{DD} , V _{SS}	±3.5 or 7	V	
Differential input voltage		DV _{IN}	±7	V	
Input voltage		V _{IN}	$V_{SS} \sim V_{DD}$	V	
Output Current		lout	±35	mA	
Power dissipation	TC75S56F/FU	P _D	200	mW	
	TC75S56FE		100		
Operating tempera	erating temperature		-40~85	°C	
Storage temperature		T _{stg}	−55~125	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note: This device's CMOS structure makes it prone to latch-up. To prevent latch-up, please take the following precautions:

- Ensure that no I/O pin's voltage level ever exceeds V_{DD} or drops below V_{SS}.
 In addition, check the power-on timing.
- Do not subject the device to excessive noise.

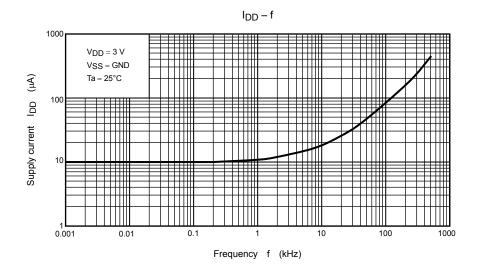
Electrical Characteristics (unless otherwise specified, $V_{DD} = 5 \text{ V}$, $V_{SS} = GND$, $Ta = 25^{\circ}C$)

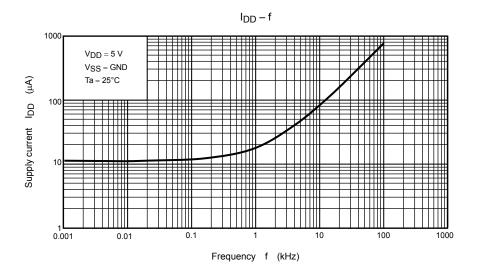
Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V _{IO}	_	_	_	±1	±7	mV
Input offset current	I _{IO}	_	_	_	1	_	pА
Input bias current	lį	_	_	_	1	_	pА
Common mode input voltage	CMV _{IN}	_	_	0	_	4.1	V
Supply current	I _{DD} (Note)	_	_	_	11	22	μА
Voltage gain	G _V	_	_	_	94	_	dB
Sink current	I _{sink}	_	V _{OL} = 0.5 V	13	25	_	mA
Source current	I _{source}	_	V _{OH} = 4.5 V	9	21	_	mA
Output valtage	V _{OL}	_	I _{sink} = 5.0 mA	_	0.1	0.3	· V
Output voltage	V _{OH}	_	I _{source} = 5.0 mA	4.7	4.9	_	
Operating supply voltage	V_{DD}	_	_	1.8	_	7.0	V
Propagation delay time (turn on)	t _{PLH} (1)	_	Over drive = 100 mV	_	680	_	- ns
Propagation delay time (turn on)	t _{PLH} (2)	_	TTL step input	_	500	_	
Draw a setion dalay time (turn off)	t _{PHL} (1)	_	Over drive = 100 mV	_	250	_	- ns
Propagation delay time (turn off)	t _{PHL} (2)	_	TTL step input	_	380	_	
Posnonso timo	t _{TLH}	—	Over drive = 100 mV	_	60	_	- ns
Response time	t _{THL}	—	Over drive = 100 mV	_	8	_	

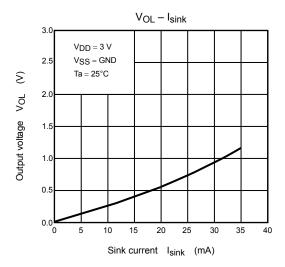
Electrical Characteristics (unless otherwise specified, $V_{DD} = 3 \text{ V}$, $V_{SS} = GND$, $Ta = 25^{\circ}\text{C}$)

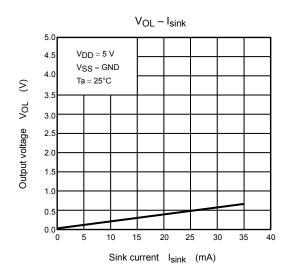
Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V _{IO}	_	_	_	±1	±7	mV
Input offset current	I _{IO}	_	_	_	1	_	pA
Input bias current	lį	_	_	_	1	_	pA
Common mode input voltage	CMV _{IN}	_	_	0	_	2.1	V
Supply current	I _{DD} (Note)	_	_	_	10	20	μА
Sink current	I _{sink}	_	V _{OL} = 0.5 V	6	18	_	mA
Source current	I _{source}	_	V _{OH} = 2.5 V	3	15	_	mA
Output valtage	V _{OL}	_	I _{sink} = 5.0 mA	_	0.15	0.35	V
Output voltage	V _{OH}	_	I _{source} = 5.0 mA	2.65	2.85	_	
Propagation delay time (turn on)	t _{PLH}	_	Over drive = 100 mV	_	550	_	ns
Propagation delay time (turn off)	t _{PHL}	_	Over drive = 100 mV	_	250	_	ns
Response time	t _{TLH}	_	Over drive = 100 mV	_	30	_	no
	t _{THL}	_	Over drive = 100 mV		8		ns

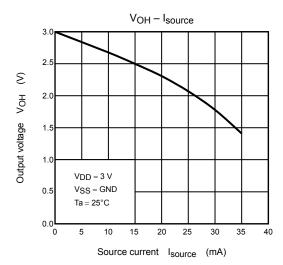
Note: This device's current consumption increases as its operating frequency increases. Note that the power dissipation should not exceed the allowable power dissipation.

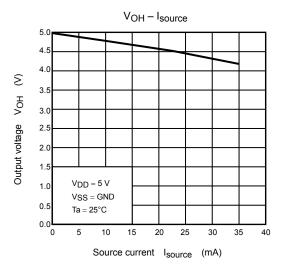


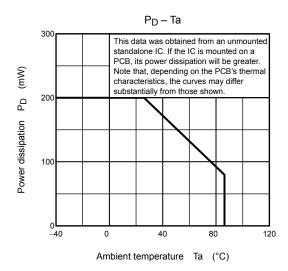




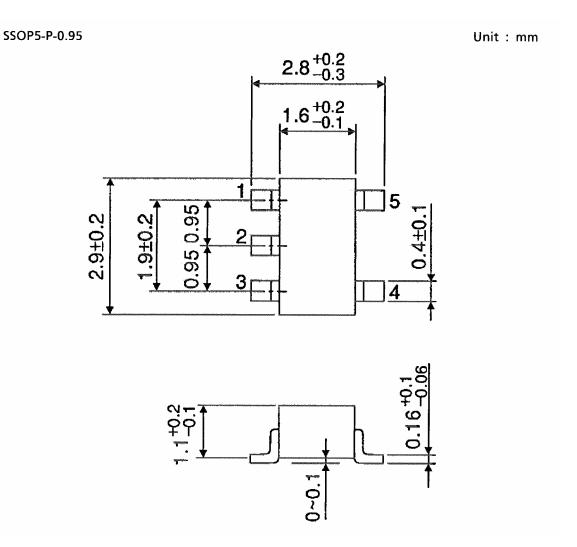








Package Dimensions

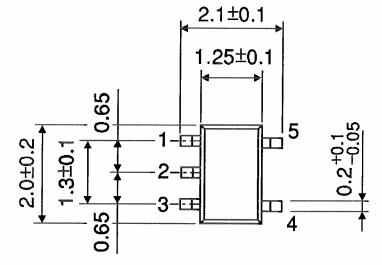


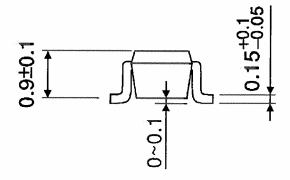
Weight: 0.014 g (typ.)

Package Dimensions

TOSHIBA

SSOP5-P-0.65A Unit: mm



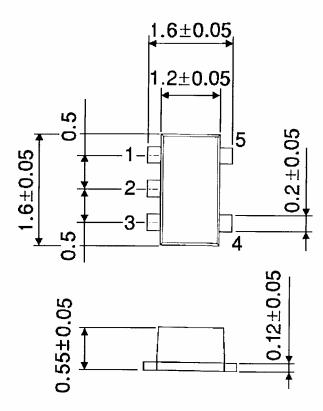


Weight: 0.006 g (typ.)



Package Dimensions

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

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20070701-EN GENERAL

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